Search Notes

Application/Control No.	Applicant(s)/Patent un Reexamination	der
10/767,614	OGAWA, HIDEHIKO	
Examiner	Art Unit	
Thomas D. Lee	2624	

SEARCHED					
Class	Subclass	Date	Examiner		
358	1.15, 402, 440	6/6/2005	TDL		
379	100.01	6/6/2005	TDL		
379	100.08	6/6/2005	TDL		
379	100.13	6/6/2005	TDL		
. 379	100.17	6/6/2005	TDL		
updated		9/14/2005	TDL		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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